East Seineh fin Phycr 10. 12

L Number	Hits	Search Text	DB /	Time stamp
- Wallase I	88	overlay adj target	USPAT; MS-PGPUB; EPO; JPO; DERWENT; IBM TOB	2002/32/14
	Ö	77044203.URPN.	YUFAT	2002 (02 /14 17:21
-	12	"5877761" "5776645"	USPAT; US-PGFUB; EIO; JPO; IEFWENT; IFM TDB	2002 102 114 17:49
-	10119	alignment adj mark	UPFAT; US-PGPUB; EFU; CPO; LEEWENT; LIM TED	2002'02'14
-	4777	(alignment adj mark) and substrate	UCPAT: UCPPGPUH; EFO: JFO: DERWENT: TEM TUB	2(02 '02 14 17:5)
-	198	(alignment adj mark) and residue	USPAT; USPGFUE; EFO; JF; DEPWENT; IEM TIF	2(02-02/14 17:5)
-	5	((alignment adj mark) and residue) and residue with (improve increase registration register)	US: AT; US-PGIUE; EPC; UFO; LERWENT; IEM TIE	2002/02/14 17:55
_	3	((alignment adj mark: and residue) and residue with (lower decrease)	USIAT; US-PGPUB; EFO; JFO; LEFWENT; IBM TDE	2002,02,14 17:50
-	1	<pre>(((alignment adj mark) and residue) and residue with (improve increase registration register)) and (((alignment adj mark) and residue) and residue with (lower decrease))</pre>	USFĀT; US-PGPUE; EPO; JEO; LFÁWENT: LEM TDF	2002/02/14 17:56
-	7	<pre>(((alignment adj mark) and residue) and residue with (improve increase registration register)) (((alignment adj mark) and residue) and residue with +lower decrease*)</pre>	USPAT; USPECUE; FEQ; JEO; IEFWENT: IEM TOE	2002732714 17:56
-	•	realignment add marks and residues and residue with improve increase registration register alignment add mark and recidue with slower degreases.	USPĀT; USPĀT; USPEGEUN; SELVEUT; ISM_TDE	
-		(:257/797 or (438/401,462,975)).ccls.	USFAT; USFPGPUB; EFO; JFO; DERWENT; IEM_TDB	
	458	<pre>**(*257/797) or **438*401,462,975 %.ccbs.**</pre>	USPĀT;	2002/12 14 11.11

*) + 1, + IFFWEUT: IEM TIE

-	3	5982044.URPN.	USPAT	2002/02/14 18:13
-	13	("3793044" "5128283" "5316966" "5356513" "5578519" "5627110" "5877562" "5889335" "5893744" "59111(8" "5946583" "5950093" "5962044").PN.	JSPAT	2002/02/14 19:23
_	10	6143133.URPN.	USPAT	2002 02/14 18:25
_		("3600241" "3802940" "4134066" "4233091" "4356223" "4640988" "4642672").PN.	USPAT	2002/02/14
_	17	5128293.URPN.	USPAT	2002 02 14 18:2 1
-	151	((((257/797) or (438/401,462,975)).CCLS.) and resist) and patterning	USPAT; US-PGPUB; EPO; JPO; LEHWENT; LBM TOB	
-	119	(((((257/797) or (438/401,462,975)).CCLS.) and resist) and patterning) and etching	USIAT; US-PGFUE; EPC; JPO; IEFWENT; IBM TUB	2002 32'14 18:5.
-	60	((((((257/797) or $(438/401,462,975)).CCLS.)$ and resist) and patterning) and etching) and etching with substrate		2002 02 15 09:13
		("4981529" "5198390" "5234868" "5314843" "5401691" "5523254" "5556808" "5622899" "5668042" "5700732" "5786260" "5801090").PN.	USFAT	2002 02,14 19:26
	€	5923996.URPN.	USFAT	2002,02,14 19:26
		("5128283" "5468464" "5523254" "5923996" "5958806" "6025652" "6271602" "6309944" "6316328" "5712717" "6130750" "5776645" "5124927" "5731877" "5805290" "6128089" "6309944" "6043153" "4590382" "5365072" "5982044" "6313517" "6008070" "5700732" "6261913" "61724 (9") [pn]	USFAT; US-PGFUB; EPG; JPO; DERWENT; IBM_TDB	2002,02,15 09:16
	25	(US-6323527-\$ or US-6316328-\$ or US-6309944-\$ or US-6271602-\$ or US-6209944-\$ or US-6271602-\$ or US-6261918-\$ or US-6172409-\$ or US-6130750-\$ or US-6128089-\$ or US-603133-\$ or US-6025652-\$ or US-6043133-\$ or US-6025652-\$ or US-6026070-\$ or US-5982044-\$ or US-5368000-\$ or US-5982044-\$ or US-5368000-\$ or US-5776645-\$ or US-5731877-\$ or US-57312707-\$ or US-5731877-\$ or US-5121707-\$ or US-546664-\$ or US-523254-\$ or US-512283-\$ or US-5124927-\$ or US-5123283-\$ or US-5124927-\$ or US-4591382-\$).did.	USPAT	2002,02/15
		(:257/797) or (438/401,462,975)).CCLS.	US-PGPUB; EPO; JPO; DEPWENT; IBM TDB	2002/02/18 10:34
	;2	nem mom i kili dok dink dan lokari i kekiki	α <u>ς Σ</u>	

that define a form with $\alpha=\alpha_{\rm tot}+\beta_{\rm tot}+\alpha_{\rm tot}+\beta_{\rm tot$

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·	51	(((1257/797) or (438/401,462,975)).CCLS.) and (method mark).tl.) and (etching with substrate) same resist		10:36
_	111	(((257/797) or (438/401,462,975)).CCLS.) and (method and mark).ti.	IBM_TDB USFAT; US-PGFUB; EPF; JPO; DEEWENT;	2002/02/15 10:36
-	4.0	and (method and mark).tily and etching with substrate	IBM TDB US:AT; US PGFUB; EF; JPO; DEEWENT;	12.17 . 14 10:36
-	2	gp-62018714-\$.did.	IBM_TIPB USFAT; US-PGPUE; EPF; JPC; DERWENT;	2002/02/15 11:0)
-	1	1985JP-0158781.ap,pra1.	IBM_TDB USPAT; US-PGFUE; DP-; JFO; DERWENT;	2002/02/15
-	9 .	deguchi and alignment adj mark	IBM_TDB USFAT; US-PGPUE; EPO; JPC; LERWENT; IBM TDB	2002/02/15 11:00
-	4	<pre>jp-62018714-\$.did. jp-63187628-\$.did.</pre>	USPĀT; US-PGPUB; EPG; JFG; DERWENT;	2002 (2115) 13:15
=	0	63187628.URPN.	IBM_TDB USFAT	2002, 02 15
-	0	63187628.UEPN.	USFAT	13:10 2002,02 15 13:14
_	1	1988-259909.NRAN.	DEFWENT	2002/02 15
_	1	1987-062200.NRAN.	DELWENT	13:14 2002.02'15
-	0 .	62018714.URPN	USFAT	13:14 2002/02/15 13:14